



OIML Certification System (OIML-CS) Implementation Accreditation in Legal Metrology

Legal Metrology Experts

Legal Metrology Experts validated by the OIML-CS Management Committee to participate in Accreditation and Peer Assessments under the OIML-CS

Expert Name	Country	OIML Recommendation																				Assessment Experience	
		R 16	R 21	R 46	R 49	R 50	R 51	R 60	R 61	R 75	R 76	R 85	R 99	R 106	R 107	R 117	R 126	R 129	R 134	R 137	R 139	ISO/IEC 17025	ISO/IEC 17065
CHEN, Yi	AU					✓	✓	✓			✓			✓	✓							✓	
ZAMORA, Mario	AU														✓								
BILS, Dirk	BE														✓						✓	✓	
MATEUS SANCHEZ, Juan Carlos ¹	BR	✓	✓	✓							✓		✓		✓	✓						✓	
FARUOLO, Luciano Bruno	BR										✓									✓		✓	
COUVREUR, Gulian	CH						✓	✓	✓		✓			✓	✓					✓		✓	✓
NIEDERHAUSER, Bernhard	CH																✓					✓	
HU, Manhong	CN					✓	✓		✓		✓				✓					✓			
JIANG, Jile	CN							✓															
SHI, Leibing	CN			✓																			
WANG, Jian	CN						✓				✓											✓	
YANG, Jing	CN														✓								
YANG, Youtao	CN																				✓		
ZHONG, Ruilin	CN					✓	✓		✓		✓				✓					✓			
ZHOU, Shaoyuan	CN			✓																			

1 For EMC tests only

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		R 16	R 21	R 46	R 49	R 50	R 51	R 60	R 61	R 75	R 76	R 85	R 99	R 106	R 107	R 117	R 126	R 129	R 134	R 137	R 139	ISO/IEC 17025	ISO/IEC 17065	
BENKOVA, Miroslava	CZ				✓										✓							✓		
KRIZ, Ivan	CZ					✓	✓		✓		✓			✓	✓					✓			✓	
VALENTA, Tomás	CZ																				✓		✓	✓
ROSE, Jürgen	DE									✓													✓	✓
SCHWABE, Timo	DE						✓																	
JENSEN, Jens Hovgård	DK				✓	✓		✓		✓					✓			✓	✓					
BRUN, Christophe	FR															✓						✓	✓	
DELETTE, Laetitia	FR																✓						✓	
LOPEZ, Luc ²	FR		✓				✓			✓	✓	✓				✓								✓
MOREL, Emeric	FR				✓																		✓	
AGARWAL, Ashutosh	IN				✓		✓					✓				✓							✓	
ZOTTI, Lucio	IT				✓																		✓	✓
AZAMI, Nobuhiko	JP							✓																
ITO, Takeshi	JP															✓							✓	
NAGANO, Tomohiro	JP											✓											✓	
OTANI, Satoshi	JP											✓											✓	
TANAKA, Yoshitada	JP							✓																
BEUMER, Erik	NL				✓					✓		✓				✓						✓	✓	
BOEREBOOM, Hans	NL			✓																				
CLOO, Marcel	NL			✓																			✓	
KOK, Paul	NL		✓			✓	✓		✓		✓		✓		✓		✓	✓	✓				✓	✓
MEIJER, Mathias	NL		✓			✓		✓			✓												✓	✓
ROOIJ, Paul van	NL				✓					✓		✓			✓					✓	✓		✓	
SCHOLTEN, Roy	NL					✓		✓		✓					✓			✓					✓	
SOEKHOE, Satish	NL														✓					✓	✓		✓	

2 Limited to assessments of OIML Issuing Authorities

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		R 16	R 21	R 46	R 49	R 50	R 51	R 60	R 61	R 75	R 76	R 85	R 99	R 106	R 107	R 117	R 126	R 129	R 134	R 137	R 139	ISO/IEC 17025	ISO/IEC 17065
TJOA, Aldemar	NL			✓	✓		✓			✓	✓	✓				✓		✓		✓		✓	
VERMEUL, Yvo	NL				✓						✓					✓				✓		✓	
WIJNGAARDEN, Carl van	NL																			✓		✓	
YILMAZ, Baris	NL						✓				✓							✓				✓	✓
BOBBALA, Srinivas	NZ										✓					✓						✓	
HATTINGH, Jaco	NZ				✓						✓											✓	
KÄLLGREN, Hakan	SE					✓	✓	✓	✓		✓			✓	✓							✓	✓
GRUM, Matej	SI					✓	✓		✓		✓			✓	✓							✓	✓
PREMUŠ, Aleksander	SI		✓	✓																		✓	✓
MAZÚR, Viliam	SK				✓																	✓	
AYDEMIR, Bülent	TR					✓	✓	✓	✓		✓			✓	✓					✓		✓	
KAÇMAZ, Sevda	TR					✓	✓	✓	✓		✓			✓	✓					✓		✓	
BOKOTA, Marek	UK				✓											✓						✓	✓
GLAS, Gregory	UK		✓			✓	✓		✓		✓			✓	✓					✓		✓	✓
JAMES, Ivor	UK											✓						✓					
Ji, Wei	UK		✓					✓			✓											✓	✓
MUNTEANU, Christine	UK										✓					✓						✓	